

Carbon Dioxide Sensing Characteristics of AlGa_N/Ga_N High Electron Mobility Transistor with ZnO Nanorods

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A CO₂ sensor based on an AlGa_N/Ga_N high electron mobility transistor (HEMT) was developed using ZnO nanorods as the sensing material. The sensor showed a reliable response to a wide range of CO₂ concentrations from 500 to 100000 ppm at 300 °C. The CO₂ response of the device was tested from 25 to 400 °C, and the sensor started to exhibit responsivity to 30000 ppm CO₂ gas at 150 °C. The responsivity increased with the ambient temperature until the temperature reached 300 °C, and it decreased from 350 to 400 °C. The maximum responsivity of the sensor with ZnO nanorods was 4.31% for 10% CO₂ exposure at 300 °C. In addition, the effect of humidity on the CO₂ sensing characteristics was investigated. AlGa_N/Ga_N-heterostructure-based CO₂ sensors functionalized with ZnO nanorods have high potential for applications in the chemical, medical, energy, and food industries.

1. Introduction

There has been much interest in CO₂ sensors for monitoring global warming, indoor air quality, process control in fermentation, and medical use.^(1,2) The concentration of atmospheric CO₂ was 280 ppm before the industrial revolution, which increased to 400 ppm with the increase in fossil fuel usage.⁽³⁾ CO₂ is colorless and odorless, and its molecular mass is 44.01 g/mol, which is heavier than air (18.02 g/mol). Hence, it easily accumulates on the ground of an enclosed space. A CO₂ concentration of more than 7% can cause acute symptoms in exposed people including unconsciousness, even in environments with high concentrations of oxygen. For example, a worker in an isolated septic tank with a high concentration of CO₂ can become unconscious and die in severe cases. CO₂ is used for reactants, intermediates, and products in the chemical, medical, energy, and food industries. It is necessary to detect promptly the specific concentration of CO₂ for the safety of workplaces and the health of workers, as well as to monitor indoor air quality in daily life.

The most conventional approach to detecting CO₂ is based on nondispersive infrared absorption sensors, which consist of an infrared source, a light tube, an interface filter,

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and an infrared detector.^(4,5) They have good sensitivity and selectivity for CO₂ sensing, but they require high power consumption, a large physical space, and a complex structure. Semiconductor-based gas sensors have many merits, such as low power consumption, compact size, sensitivity, and reliability.⁽⁵⁾ Among the many semiconductor materials, GaN-based material systems are highly suitable for gas sensing. GaN-based gas sensors exhibit high signal-to-noise ratios, and they have reliable and stable operation at high temperatures owing to their excellent material properties, such as a wide energy bandgap of 3.4 eV, chemical and mechanical robustness, excellent carrier transport, and radiation hardness.^(6–24) One of the biggest advantages of GaN-based semiconductors is the availability of the AlGaN/GaN heterostructure, in which a two-dimensional electron gas (2DEG) channel with a mobility of more than 1500 cm²/V·s forms at the interface between AlGaN and GaN due to spontaneous polarization and piezoelectric effects.^(6–9,18–24) The electron conductivity of the 2DEG is sensitive to changes in charge on the top AlGaN surface. In the sensor structure of an AlGaN/GaN high electron mobility transistor (HEMT), the gate region is functionalized with a specific catalytic material to induce the decomposition reaction of the target gas. This results in a change in surface charge on the AlGaN surface. Monitoring the drain current passing through the 2DEG in the HEMT enables the output sensing signal for the decomposition reaction of the target gas to be obtained.

ZnO is a direct-bandgap semiconducting material with a wide bandgap energy of 3.37 eV and a large exciton binding energy of 60 meV.^(25–27) ZnO nanostructures are grown by a simple hydrothermal method, which is a low-cost, nontoxic, low-temperature, and scalable process. During hydrothermal growth, the growth rate of the *c*-plane is higher than that of the *m*-plane in the wurtzite crystal structure because of the higher surface energy of the *c*-plane; ZnO nanowires or bundles of nanorods along the *c*-axis are generally formed during the hydrothermal synthesis process.^(27–30) These ZnO nanorods with high surface-to-volume ratio can be employed in AlGaN/GaN HEMT gas sensors in the gate region to achieve high sensitivity to the target gas.

In this research, an AlGaN/GaN HEMT-based CO₂ sensor using ZnO nanorods as a sensing material was fabricated, and its CO₂ sensing characteristics were investigated. The effects of temperature, CO₂ concentration, and humidity on the CO₂ responsivity were studied.

2. Materials and Methods

The AlGaN/GaN heterostructure was grown by metal organic chemical vapor deposition on a *c*-plane Al₂O₃ substrate.^(6–9) The epitaxial layer consisted of 2.5 μm GaN and 30 nm Al_{0.3}GaN. The sheet resistance, sheet carrier concentration, and carrier mobility of the AlGaN/GaN heterostructure were 320 ohm/square, 9×10^{12} cm⁻², and 1800 cm²/V·s, respectively. Figure 1 shows a top-view scanning electron microscopy (SEM) image of the HEMT with ZnO nanorods on the gate region and a schematic cross-sectional diagram of the HEMT structure along the cutline of A–A' in (a). The fabrication of the device started with 75 nm mesa isolation achieved by inductively coupled plasma etching with Ar/Cl₂ gas. A 20 nm Ti/80 nm Al/40 nm Ni/80 nm Au metal stack was deposited by electron beam

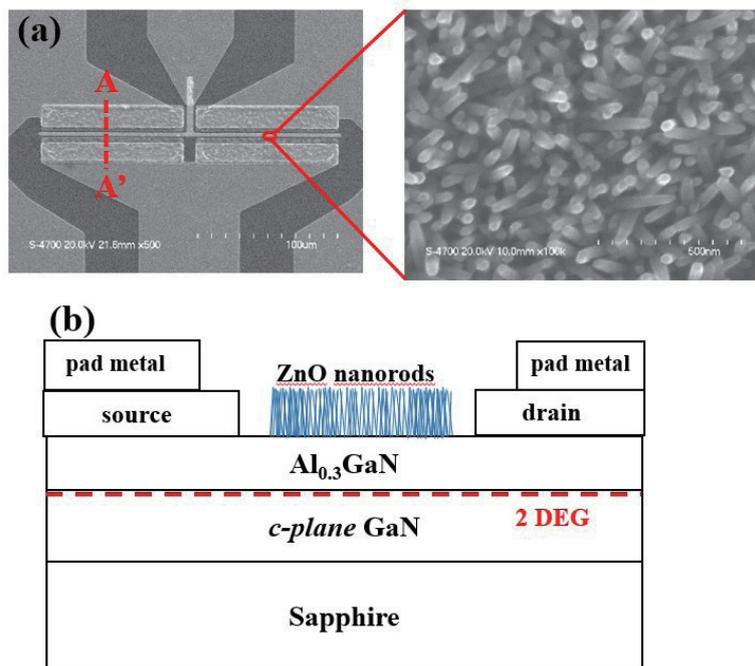


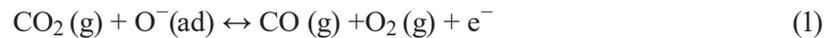
Fig. 1. (Color online) (a) Top-view SEM image of the HEMT with ZnO nanorods and enlarged image of the ZnO nanorods. (b) Schematic cross-sectional diagram of the HEMT structure along the cutline of A–A' in (a).

evaporation, and the stack was annealed at 950 °C for 1 min under a N₂ atmosphere by rapid thermal annealing for ohmic contact formation. A 20 nm Ti/120 nm Au pad metal was formed by electron beam evaporation for electrical signal probing. ZnO nanorods were selectively grown on the gate area by conventional photolithography, a simple hydrothermal ZnO nanorod growth method,^(27–30) and a lift-off process. A 25 mM solution of zinc nitrate hexahydrate was dissolved in deionized water, and a 25 mM methenamine solution was prepared. These two solutions were mixed together equivolumetrically in a Teflon-lined autoclave to prepare a growth solution. The fabricated AlGaN/GaN HEMT substrate was suspended upside down in the growth solution and was placed in a 90 °C oven for 90 min. After the growth, the sample was removed, washed with deionized water vigorously, and blow-dried with nitrogen. This growth cycle was repeated five times to obtain dense ZnO nanorods with a high aspect ratio. The length and diameter of the ZnO nanorods were approximately 1 μm and 50 nm, respectively.

The drain current–voltage characteristics and current response of the HEMT sensor with ZnO nanorods were measured using an Agilent 4156C semiconductor parameter analyzer with the device in a gas test chamber under ambient conditions of various concentrations of CO₂ in air. The temperature and humidity of the test ambient conditions were controlled respectively by the heater chuck on which the sample was placed and the humidity controller connected to the gas test chamber.

3. Results and Discussion

Figure 2 shows the drain I - V characteristics of the AlGaIn/GaN HEMT with ZnO nanorods under air and a 10% CO₂ atmosphere at 300 °C. When the device was exposed to CO₂ gas, the drain current increased. In the AlGaIn/GaN heterostructure, a 2DEG channel layer exists underneath the AlGaIn owing to polarization and piezoelectric effects, as shown in Fig. 1(b).^(6–9,18,19) The conductivity of the 2DEG channel was affected sensitively by the change in charge on the AlGaIn surface. If a reaction inducing the change in surface charge on the AlGaIn surface by a target gas occurs, the conductivity of the 2DEG changes, resulting in a change in the drain current of the AlGaIn/GaN HEMT. In the case of the CO₂ atmosphere, the possible sensing mechanism of the AlGaIn/GaN HEMT with ZnO nanorods is described as follows. ZnO is known to adsorb oxygen ions on the surface.^(1,2,5) The exposed CO₂ gas molecules react with the adsorbed O[−] and release electrons with a negative charge. These electrons make the oxide more negative and induce an additional positive charge on the AlGaIn surface, which enhances the 2DEG channel by accumulating more electrons and increasing the drain current of the device.



It is notable that the increase in drain current upon CO₂ exposure is opposite to the case of reducing NH₃ gas in an AlGaIn/GaN HEMT with ZnO nanorods.^(20,21)

The responses of the AlGaIn/GaN HEMT functionalized by ZnO nanorods to sequential 10 s exposures of 100% N₂ and 300–100000 ppm CO₂ in dry air at 150 and 300 °C are shown in Fig. 3. The drain bias voltage was fixed at 1 V. The device was tested under the same conditions at 25 to 400 °C in 50 °C increments, but no response to CO₂ was observed at 25, 50, and 100 °C. At 150 °C, the HEMT with ZnO nanorods started to respond to 30000 ppm CO₂, but the drain current signal was unclear. In contrast, distinctive changes in current for exposures to various

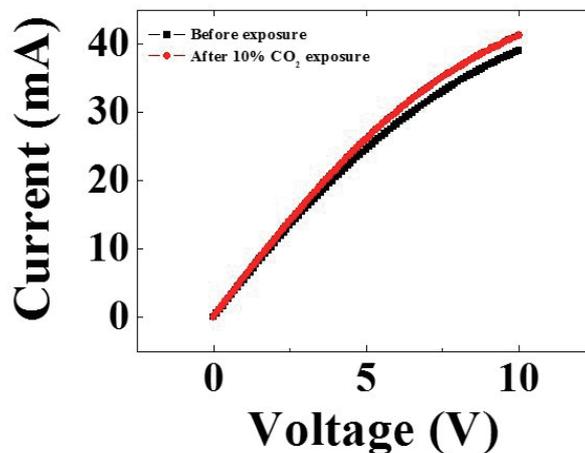


Fig. 2. (Color online) Drain current response of the HEMT sensor to air and 10% CO₂ exposure at 300 °C.

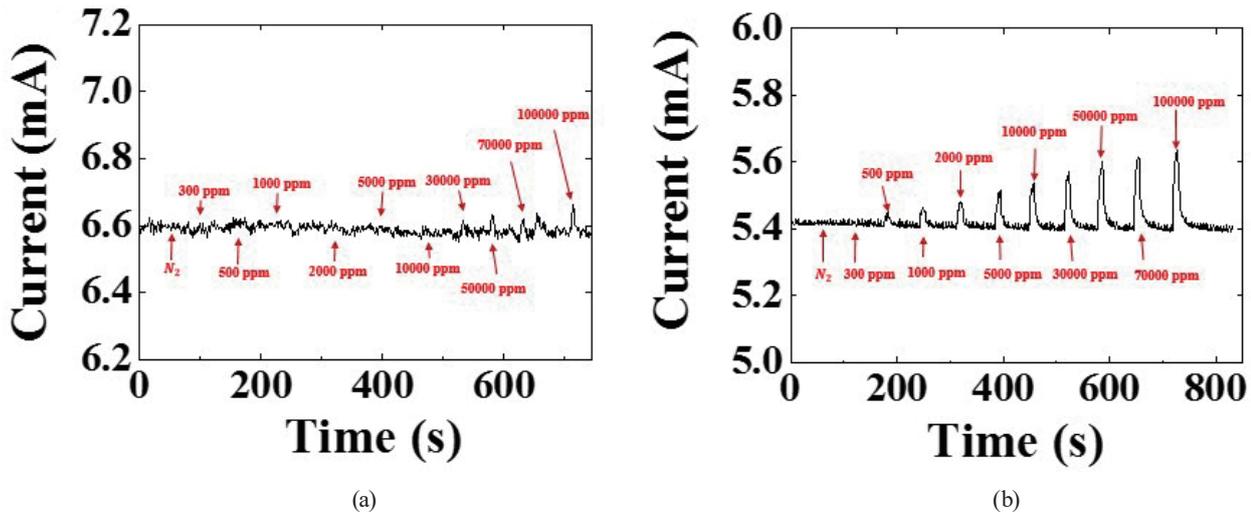


Fig. 3. (Color online) Time-dependent responses of the HEMT to 100% N_2 and 300–100000 ppm CO_2 at 150 and 300 °C. The drain bias was 1 V and the gas exposure time was 10 s.

concentrations of CO_2 were observed at 300 °C. The drain current returned to the original level after switching back to air. The minimum measurable concentration of CO_2 was 500 ppm. The AlGaIn/GaN HEMT with ZnO nanorods showed reliable repeatability for cyclic exposures with various concentrations of CO_2 at 300 °C.

Figure 4 shows the responsivity of the HEMT sensor to 300–100000 ppm (10%) concentrations of CO_2 at 150, 200, 250, 300, 350, and 400 °C. The responsivity is defined as $(I_{CO_2} - I_{air}) / I_{CO_2} \times 100$ (%), where I_{CO_2} and I_{air} are the drain currents of the HEMT at 1 V under CO_2 and ambient air, respectively. As the CO_2 concentration increases, the responsivity increases and saturates at high CO_2 concentrations. The HEMT responsivity for 10% CO_2 at 300 °C was 4.31%. The responsivity increased with the ambient temperature until reaching 300 °C, and it decreased at 350 and 400 °C. The oxygen ions adsorbed on the ZnO surface exist in the form of O_2^- , O^- , and O^{2-} . The O_2^- , O^- , and O^{2-} ions are stable below 100 °C, between 100 and 300 °C, and above 300 °C, respectively.^(1,31) The rate of the forward reaction of Reaction (1) may increase with the concentration of adsorbed oxygen ions, O^- , up to 300 °C; hence, the device shows maximum responsivity at 300 °C. This temperature dependence of the responsivity can also be found in the case of ZnO thin-film CO_2 sensors.⁽¹⁾

The responsivity at 300 °C was modeled using the dissociative Langmuir isotherm given below, as shown in Fig. 5,^(6,32)

$$R = \frac{\alpha (K_{eq} \cdot C)^{\frac{1}{2}}}{1 + (K_{eq} \cdot C)^{\frac{1}{2}}}, \quad (2)$$

where R is the responsivity, α is the proportionality constant, K_{eq} is the equilibrium constant of the adsorption, and C is the concentration of CO_2 . The plot shows good agreement with the

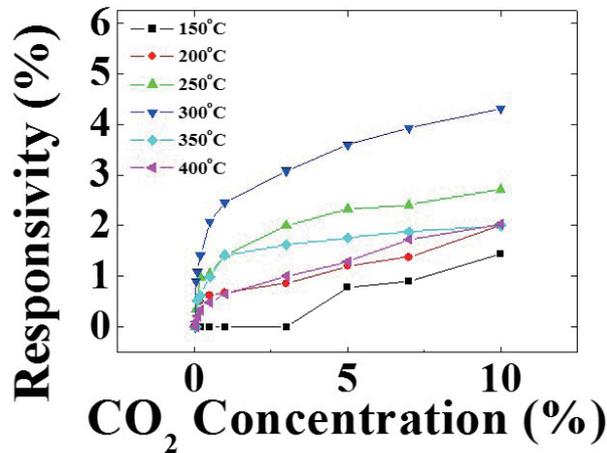


Fig. 4. (Color online) Responsivity of the HEMT sensor to different concentrations of CO₂ at 150, 200, 250, 300, 350, and 400 °C.

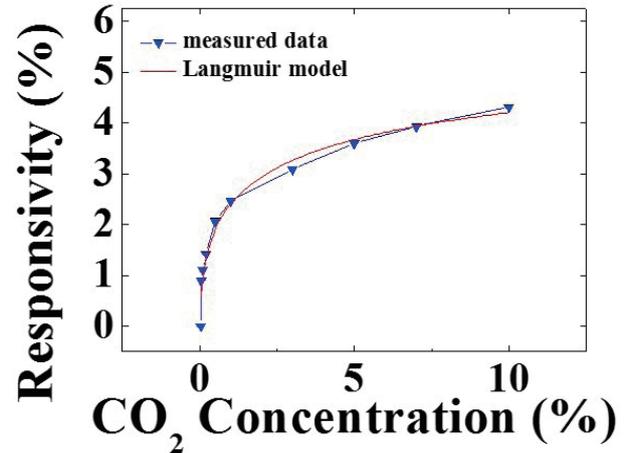


Fig. 5. (Color online) Responsivity of the HEMT to different concentrations of CO₂ at 300 °C and its Langmuir isotherm fitting model.

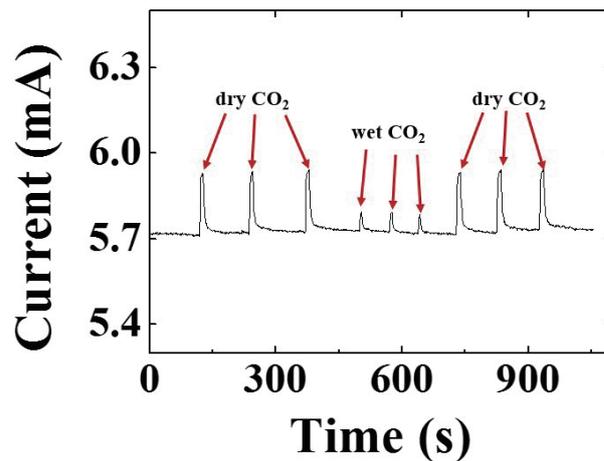


Fig. 6. (Color online) Change in drain current of the HEMT at 300 °C for cyclic exposures of dry, wet, and dry 10% CO₂.

measured and calculated data. The equilibrium constant of the AlGaIn/GaN HEMT with ZnO nanorods at 300 °C was 0.346.

The effect of humidity on CO₂ sensing was investigated. Figure 6 shows the change in drain current of the HEMT with ZnO nanorods at 300 °C for cyclic exposures of dry, wet, and dry 10% CO₂. The bias voltage was 1 V, and each 10 s of CO₂ exposure was repeated three times. The relative humidity was 77% for a wet CO₂ environment at 300 °C. The change in drain current decreased by 64% under a humid ambient condition compared with the case of dry CO₂ exposure, even at a high temperature of 300 °C. Under wet CO₂ conditions, H₂O molecules were adsorbed on the surface of ZnO nanorods and prevented CO₂ molecules from reacting with oxygen ions on the active sites of the nanorods, reducing the change in drain current.⁽²⁵⁾

This deteriorating effect of humidity can be overcome by employing polyimide-based moisture barrier encapsulation with a high glass transition temperature, which enables CO₂ molecules to penetrate but blocks H₂O.^(6–9,25)

5. Conclusions

An AlGaIn/GaN HEMT with ZnO nanorods on the gate region was shown to be capable of CO₂ detection from 150 °C. The device demonstrated reliable sensing characteristics for the CO₂ concentration range from 500 to 100000 ppm at 300 °C. The maximum responsivity of the sensor for 10% CO₂ exposure was 4.31%. The CO₂-sensing capability of the HEMT increased with ambient temperature until it reached 300 °C; then, it decreased at 350 and 400 °C. When wet CO₂ was introduced to the HEMT sensor, the responsivity dropped by 64% at 300 °C because the active sites of the ZnO nanorods were blocked by H₂O molecules.

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